

07/16/2005

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,767,840 B1
DATED : July 27, 2004
INVENTOR(S) : Uehara et al.

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title page.

Item [56], **References Cited**, FOREIGN PATENT DOCUMENTS, delete
“JP 0 319 806 6/1989”
“JP 1-304733 8/1989”

Column 7.

Line 33, “further” begins a new paragraph.

Column 10.

Line 5, delete “FIG. 1E” and insert -- FIG. 10E --

Column 12.

Line 26, delete “(° C.)” and insert -- (° C) --

Line 29, delete “200-μm” and insert -- 200-nm --

Line 63, delete “201-μm ± 4μm” and insert -- 201 nm ± 4 nm --

Column 13.

Line 2, delete “0.2 μm” and insert -- 0.2 nm --

Line 62, delete “(° C.) and insert -- (° C) --

Column 14.

Line 46, delete “surface-roughness” and insert -- surface roughness --

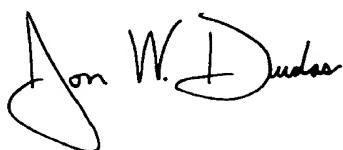
Column 16.

Line 1, delete “acid, p1 (d)” and insert -- acid (d) --

Line 57, delete “layer-on” and insert -- layer on --

Signed and Sealed this

Nineteenth Day of April, 2005



JON W. DUDAS
Director of the United States Patent and Trademark Office